



UNITED STATES PATENT AND TRADEMARK OFFICE

UNITED STATES DEPARTMENT OF COMMERCE
 United States Patent and Trademark Office
 Address: COMMISSIONER FOR PATENTS
 P.O. Box 1450
 Alexandria, Virginia 22313-1450
 www.uspto.gov



Bib Data Sheet

CONFIRMATION NO. 9102

SERIAL NUMBER 10/721,903	FILING DATE 11/26/2003 RULE	CLASS 355	GROUP ART UNIT 2851	ATTORNEY DOCKET NO. 03180.0342
-----------------------------	---------------------------------------	--------------	------------------------	-----------------------------------

APPLICANTS

Nobuhiro Komine, Yokohama-shi, JAPAN;

** CONTINUING DATA *****

** FOREIGN APPLICATIONS *****

JAPAN P2002-342798 11/26/2002 *DR*

IF REQUIRED, FOREIGN FILING LICENSE GRANTED

** 05/22/2004

Foreign Priority claimed <input checked="" type="checkbox"/> yes <input type="checkbox"/> no	STATE OR	SHEETS	TOTAL	INDEPENDENT
35 USC 119 (a-d) conditions met <input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after Allowance	COUNTRY	DRAWING	CLAIMS	CLAIMS
Verified and Acknowledged Examiner's Signature <i>[Signature]</i> Initials	JAPAN	12	25	4

ADDRESS

22852
 FINNEGAN, HENDERSON, FARABOW, GARRETT & DUNNER
 LLP
 901 NEW YORK AVENUE, NW
 WASHINGTON, DC
 20001-4413

TITLE

Reticle, exposure monitoring method, exposure method and manufacturing method for semiconductor device

FILING FEE RECEIVED 1076	FEES: Authority has been given in Paper No. _____ to charge/credit DEPOSIT ACCOUNT No. _____ for following:	<input type="checkbox"/> All Fees <input type="checkbox"/> 1.16 Fees (Filing) <input type="checkbox"/> 1.17 Fees (Processing Ext. of time) <input type="checkbox"/> 1.18 Fees (Issue) <input type="checkbox"/> Other _____ <input type="checkbox"/> Credit
------------------------------------	---	---